

Abstract of the Disclosure

Image analysis techniques may be provided. Location of objects in an image may be determined based on intensity characteristics of pixels in the image.

- 5 Objects that have been located may be mapped to a source for the objects based for example, on a grid structure that may have been used to place the objects. Differential analysis of objects of two source materials in images may be determined based on aligned
- 10 versions of the images. Filtering may be used to weigh pixel characteristics. Such object analysis techniques may have been encoded into a set of machine-executable instructions and stored on a machine-readable storage medium for use by equipment that is to perform the
- 15 techniques.